

Search Notes

Application/Control No.

09/925,259

Examiner

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Applicant(s)/Patent under
Reexamination

ADAMS ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	9/05	DN
	6	/	/
	7	/	/
	8	/	/
	26		
703	1		
	6		
706	46		
	45		
707	6		
	3		
	223	✓	✓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
I	US Patent US PG Pub	9/05 DN
II	FOREIGN	
	1. EPO 2. JPO 3. Derwent	✓ ✓
	4. IBM - TDB 5. Derwent	✓ ✓